ACPM-7381-TR1 UMTS2100 4x4 Power Amplifier (1920-1980MHz)

Data Sheet

Description

The ACPM-7381, a Wide-band Code Division Multiple Access(WCDMA) Power Amplifier (PA), is a fully matched 10-pin surface mount module developed for WCDMA handset applications. This power amplifier module is developed to cover 1920-1980MHz bandwidth. The ACPM-7381 meets the stringent WCDMA linearity requirements for output power of up to 28dBm. The ACPM-7381 is also developed to meet HSDPA specs.

The ACPM-7381 is designed to enhance the efficiency at low and medium output power range by using 3-mode control scheme with 2 mode control pins. This provides extended talk time.

The ACPM-7381 is self contained, incorporating 500hm input and output matching networks.

Order information

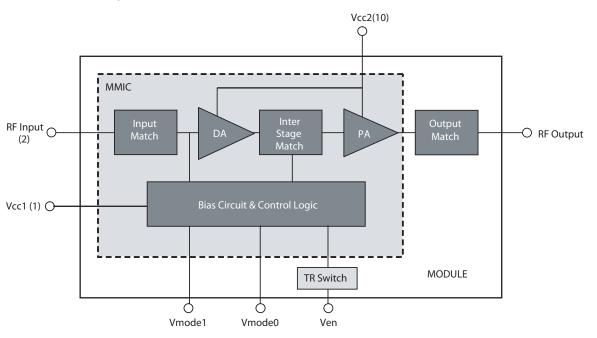
Part Number	No. of Devices	Container
ACPM-7381-TR1	1000	7" Tape and Reel
ACPM-7381-BLK	100	BULK

Features

- Excellent Linearity
- Low quiescent current
- High Efficiency PAE at 28 dBm: 39.8% PAE at 16dBm: 15.3% PAE at 8dBm: 6.0%
- 10-pin surface mounting package 4mmx4mmx1.1mm(typ)
- Internal 500hm matching networks for both RF input and output
- RoHS Compliant

Applications

• WCDMA Handset (HSDPA)



Functional Block Diagram



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Table 1. Absolute Maximum Ratings^[1]

Parameter	Symbol	Min	Nominal	Max	Unit
RF Input Power	Pin	_	_	10.0	dBm
DC Supply Voltage	Vcc	0	3.4	5.0	V
Enable Voltage	Ven	0	2.6	3.3	V
Mode Control Voltage	Vmode0	0	2.6	3.3	V
	Vmode1	0	2.6	3.3	V
Storage Temperature	Tstg	-55	_	+125	°C

Table 2. Recommended Operating Condition

Parameter	Symbol	Min	Nominal	Max	Unit
DC Supply Voltage	Vcc	3.2	3.4	4.2	V
PA Enable (Ven)	Low	0	0	0.5	V
	High	1.9	2.6	2.9	V
Mode Control Voltage					
– Vmode0	Low	0	0	0.5	V
	High	1.9	2.6	2.9	V
– Vmode1	Low	0	0	0.5	V
	High	1.9	2.6	2.9	V
Operating Frequency	Fo	1920		1980	MHz
Case Temperature	Та	-20	25	90	°C
Case Temperature	Та	-20	25	90	

Table 3. Power Range Truth Table

Power Mode	Symbol	Ven	Vmode0	Vmode1	Range
High Power Mode	PR3	High	Low	Low	~ 28dBm
Mid Power Mode	PR2	High	High	Low	~ 16dBm
Low Power Mode	PR1	High	High	High	~ 8dBm
Shut Down Mode	_	Low	-	-	-

Notes:

1. No damage assuming only one parameter is set at limit at a time with all other parameters set at or below nominal value.

Characteristics		Symbol	Condition	Min.	Тур.	Max.	Unit
Operating Frequency Range		F		1920	-	1980	MHz
Gain		Gain_hi	High Power Mode, Pout=28dBm	23.5	27		dB
		Gain_mid	Mid Power Mode, Pout=16dBm 13.5 1		17		dB
		Gain_low	Low Power Mode, Pout=8dBm	13	16.5		dB
Power Added Effici	iency	PAE_hi	High Power Mode, Pout=28dBm	34.9	39.8		%
		PAE_mid	Mid Power Mode, Pout=16dBm	11.8	15.3		%
		PAE_low	Low Power Mode, Pout=8dBm	4.2	6.0		%
Total Supply Curre	nt	lcc_hi	High Power Mode, Pout=28dBm		465	560	mA
		lcc_mid	Mid Power Mode, Pout=16dBm		75	97	mA
		lcc_low	Low Power Mode, Pout=8dBm		30	43	mA
Quiescent Current		lq_hi	High Power Mode		96	120	mA
		lq_mid	Mid Power Mode		20	26	mA
		lq_low	Low Power Mode		14	18	mA
Enable Current		len_hi	High Power Mode		0.18	1	mA
		len_mid	Mid Power Mode		0.18	1	mA
			Low Power Mode		0.18	1	mA
Control Current		Imode0_mid	Mid Power Mode	Mid Power Mode 0.4		1	mA
		Imode1_low	Low Power Mode		0.18	1	mA
		Imode0_low	Low Power Mode		0.4	1	mA
Total Current in Po	wer-down mode	lpd	Ven=0V		0.2	5	μA
Adjacent Channel Leakage Ratio ^[2]	5 MHz offset 10 MHz offset	ACLR1_hi ACLR2_hi	High Power Mode, Pout=28dBm		-43 -54	-37 -46	dBc dBc
	5 MHz offset 10 MHz offset	ACLR1_mid ACLR2_mid	Mid Power Mode, Pout=16dBm		-42 -63	-37 -46	dBc dBc
	5 MHz offset 10 MHz offset	ACLR1_low ACLR2_low	Low Power Mode, Pout=8dBm		-45 -60	-37 -46	dBc dBc
Harmonic Suppression	Second Third	2f0 3f0	High Power Mode, Pout=28dBm		-42 -69	-35 -50	dBc dBc
Input VSWR VSWR					1.8:1	2.2:1	
Stability (Spurious Output)		S	VSWR 6:1, All phase			-60	dBc
Noise Power in Rx	Band	RxBN	High Power Mode, Pout=28dBm		-138	-135	dBm/ł
Phase Discontinuity		PDlow_mid PDmid_high	low power mode ↔ mid power mode, at Pout=8dBm mid power mode ↔ high power mode, at Pout=16dBm			10 15	deg deg
Ruggedness		Ru	Pout<28dBm, Pin<10dBm, All phase High Power Mode			10:1	VSWR

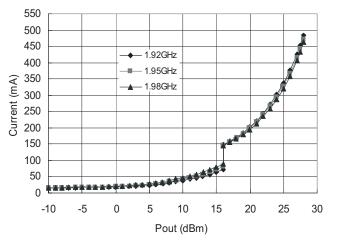
Notes:

Electrical characteristics are specified under WCDMA modulated (3GPP Uplink DPCCH + 1DPDCH) signal
 ACP is expressed as a ratio of total adjacent power to signal power, both with 3.84MHz bandwidth at specified offsets.

Characteristics		Symbol	Condition	Min.	Тур.	Max.	Unit
Operating Frequency Rang	le	F		1920	-	1980	MHz
Gain		Gain_hih	High Power Mode, Pout=27dBm	23.5	27		dB
		Gain_midh	Mid Power Mode, Pout=16dBm	13.5	17		dB
		Gain_lowh	Low Power Mode, Pout=8dBm	13	16.5		dB
Power Added Efficiency		PAE_hih	High Power Mode, Pout=27dBm	31.3	36.3		%
		PAE_midh	Mid Power Mode, Pout=16dBm	12.7	15.7		%
		PAE_lowh	Low Power Mode, Pout=8dBm	4.2	6		%
Total Supply Current		lcc_hih	High Power Mode, Pout=27dBm		405	470	mA
		lcc_midh	Mid Power Mode, Pout=16dBm		73	95	mA
		lcc_lowh	Low Power Mode, Pout=8dBm		30	43	mA
Adjacent Channel Leakage Ratio [2]	5 MHz offset 10 MHz offset	ACLR1_hih ACLR2_hih	High Power Mode, Pout=27dBm	-	-41 -56	-37 -46	dBc dBc
	5 MHz offset 10 MHz offset	ACLR1_midh ACLR2_midh	Mid Power Mode, Pout=16dBm	_	-39 -61	-37 -46	dBc dBc
	5 MHz offset 10 MHz offset	ACLR1_lowh ACLR2_lowh	Low Power Mode, Pout=8dBm	-	-44 -58	-37 -46	dBc dBc

Notes:

1. Electrical characteristics are specified under HSDPA modulated Up-Link signal (DPCCH/DPDCH=12/15, HS-DPCCH/DPDCH=15/15) 2. ACP is expressed as a ratio of total adjacent power to signal power, both with 3.84MHz bandwidth at specified offsets



Characteristics Data (WCDMA, Vcc=3.4V, Ven=2.6V, T=25°, Zin/Zout=50ohm)

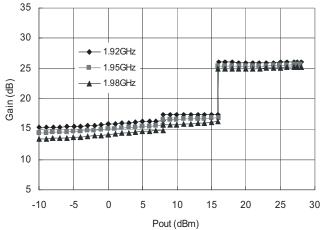
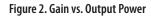


Figure 1. Total Current vs. Output Power



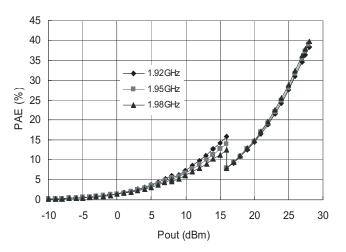


Figure 3. Power Added Efficiency vs. Output Power

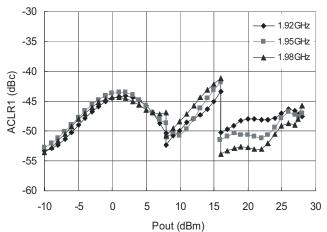


Figure 4. Adjacent Channel Leakage Ratio 1 vs. Output Power

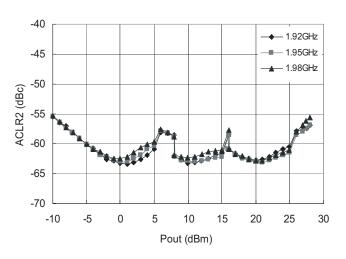
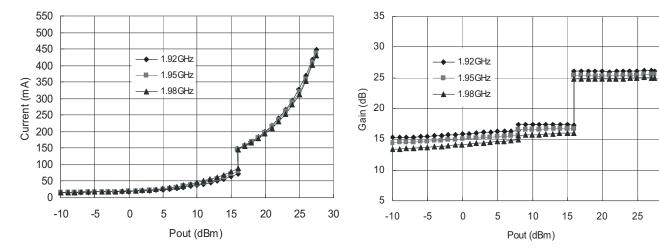
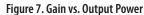


Figure 5. Adjacent Channel Leakage Ratio 2 vs. Output Power



Characteristics Data (HSDPA, Vcc=3.4V, Ven=2.6V, T=25°C, Zin/Zout=50ohm)





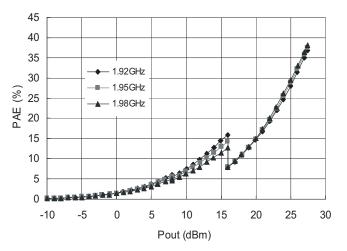
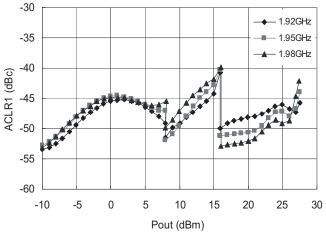


Figure 8. Power Added Efficiency vs. Output Power



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Figure 9. Adjacent Channel Leakage Ratio 1 vs. Output Power

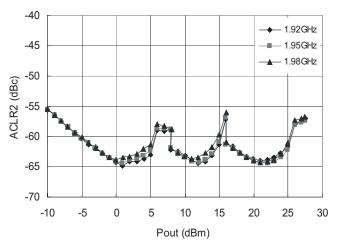


Figure 10. Adjacent Channel Leakage Ratio 2 vs. Output Power

Evaluation Board Description

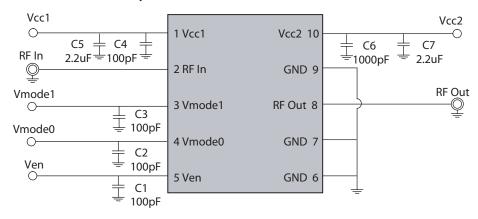


Figure 11. Evaluation Board Schematic

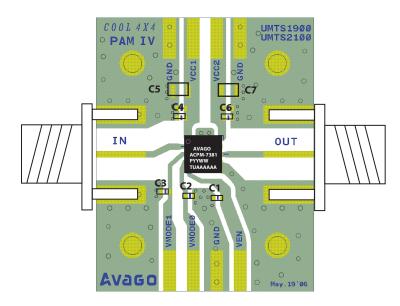


Figure 12. Evaluation Board Assembly Diagram

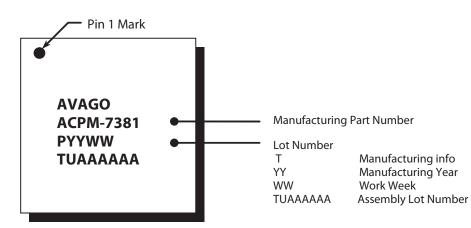
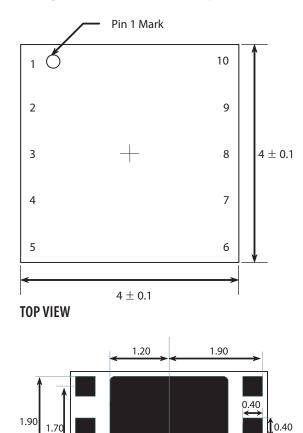
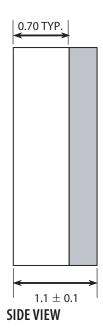


Figure 13. Marking Specifications

Package Dimensions and Pin Descriptions





Pin #	Name	Description
1	Vcc1	Supply Voltage
2	RF In	RF Input
3	Vmode1	Control Voltage
4	Vmode0	Control Voltage
5	Ven	Enable Voltage
6	GND	Ground
7	GND	Ground
8	RF Out	RF Output
9	GND	Ground
10	Vcc2	Supply Voltage

X-RAY BOTTOM VIEW

0.85

PIN DESCRIPTIONS

Figure 14. Package Dimensional Drawing and Pin Descriptions (All dimensions are in millimeters)

CoolPAM

Avago Technologies' CoolPAM is stage-bypass PA technology which saves more power compared with conventional PA. With this technology, the ACPM-7381 has very low quiescent current and efficiencies at low and medium output power ranges are very high.

Incorporation of bias circuit

The ACPM-7381 has internal bias circuit, which removes the need for external constant voltage source (LDO). PA on/off is controlled by Ven. This is digitally control pin.

3-mode power control with two mode control pins

The ACPM-7381 supports three power modes (low power mode/mid power mode/high power mode) with two mode control pins (Vmode0 and Vmode1). This control scheme enables the ACPM-7381 to save more power, which accordingly gives extended talk time.

PDF (probability density function) in Figure 15 showing distribution of output power of mobile in real field gives motivation for stage-bypass PA. Output power is less than 16dBm for most of operating time (during talking), so it is important to save power consumption at low and medium output power ranges

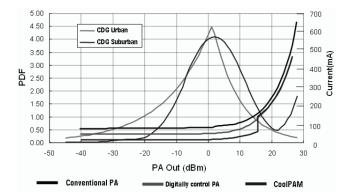


Figure 15. PDF and Current

Average current & Talk time

Average current consumed by PA can be calculated by summing up current at each output power weighted with probability. So it is expressed with integration of multiplication of current and probability at each output power.

$$Average \ current = \int (PDF \ x \ Current) dp$$

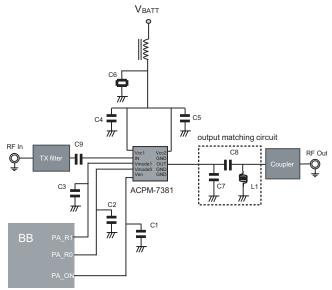
Talk time is extended more as average current consumption is lowered

Mode control pins

Vmode0 and Vmode1 are digitally controlled pins and they control operating mode of PA and truth table is summarized in table 3. These pins do not require constant voltage for interface, but high voltage input range is 1.9 though 2.9V

Application on mobile board

Figure 16 shows one application example on mobile. C4 and C5 should be placed nearby pin1 and pin10. Transmission line length after PA output should be minimized to reduce conduction loss.

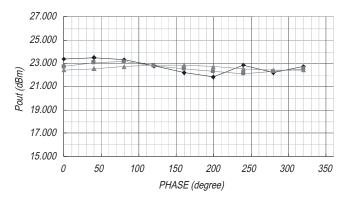




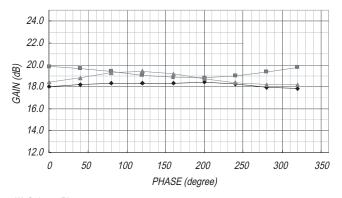
Load Insensitivity

With the trend to remove the isolator from the Tx chain in UMTS handsets, the performance demands of Load Insensitivity become dependent on the combined performance of the remaining elements in the TX chain: the power amplifier, coupler, antenna as well as the physical layout on the phone board. The ACPM-7381, as part of optimized design, meets the necessary linearity requirements over a 4:1 VSWR mismatch at the antenna plane. In the case of the ACPM-7381, the output stage has been designed for slightly higher Pout to provide the necessary margin to meet linearity under the mismatch experienced at the PA output port resulting from the forced antenna mismatch. Documentation is available that provides a more complete description of the system considerations and measurement considerations.

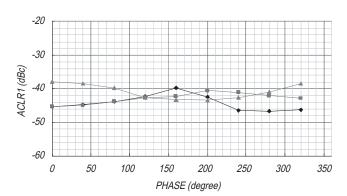
To illustrate the system performance using the ACPM-7381, Figure 17 shows measurement of TX chain with VSWR fixed at 4:1. ACLR1 is kept higher than -38dBc over all phases and gain variance is about 2dB.



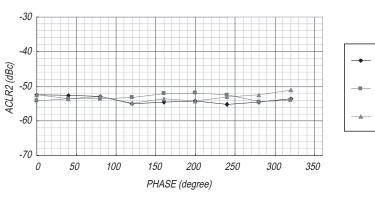




(3) Gain vs. Phase



(5) ACLR1(+5MHz Offset) vs. Phase

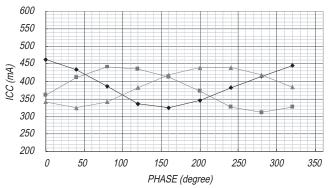


(7) ACLR2(+10MHz Offset) vs. Phase

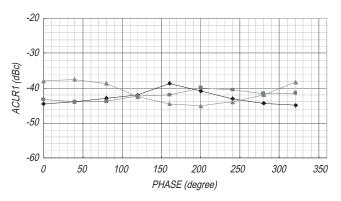
Figure 17. RF Performance of TX path with VSWR 4:1 fixed at Ant plane (Pout=24dBm)

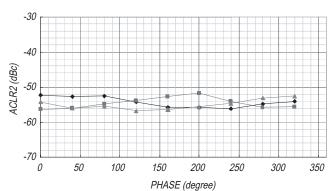


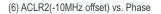
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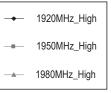








(4) ACLR1(-5MHz offset) vs. Phase



PCB Design Guidelines

The recommended ACPM-7381 PCB land pattern is shown in Figure 18 and Figure 19. The substrate is coated with solder mask between the I/O and conductive paddle to protect the gold pads from short circuit that is caused by solder bleeding/bridging.

Stencil Design Guidelines

A properly designed solder screen or stencil is required to ensure optimum amount of solder paste is deposited onto the PCB pads. The recommended stencil layout is shown in Figure 20. Reducing the stencil opening can potentially generate more voids. On the other hand, stencil openings larger than 100% will lead to excessive solder paste smear or bridging across the I/O pads or conductive paddle to adjacent I/O pads. Considering the fact that solder paste thickness will directly affect the quality of the solder joint, a good choice is to use laser cut stencil composed of 0.10mm(4mils)or 0.127mm(5mils) thick stainless steel which is capable of producing the required fine stencil outline.

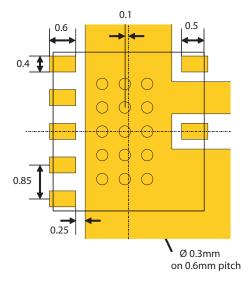
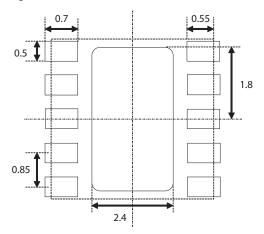


Figure 18. Metallization





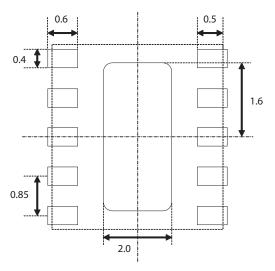
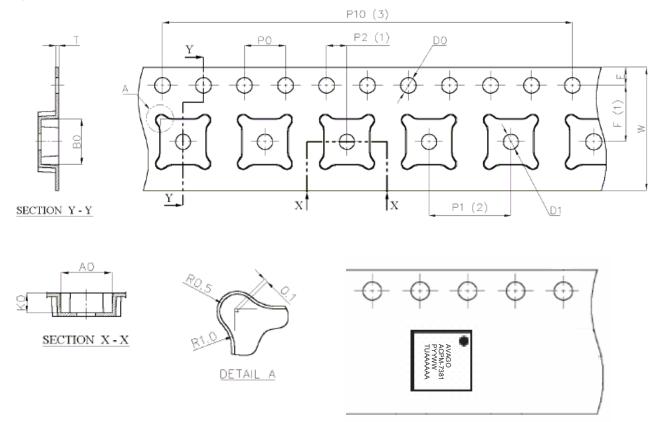


Figure 20. Solder Paste Stencil Aperture

Tape and Reel Information



Dimension List

Dimension	Millimeter
AO	4.40±0.10
BO	4.40±0.10
KO	1.70±0.10
DO	1.55±0.05
D1	1.60±0.10
PO	4.00±0.10
P1	8.00±0.10

Dimension	Millimeter
P2	2.00±0.05
P10	40.00±0.20
E	1.75±0.10
F	5.50±0.05
W	12.00±0.30
Т	0.30±0.05

Figure 21. Tape and Reel Format – 4 mm x 4 mm.

Reel Drawing

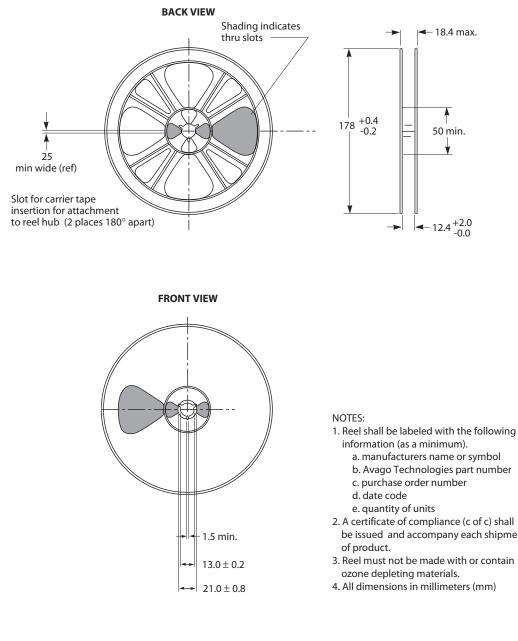


Figure 22. Plastic Reel Format (all dimensions are in millimeters)

Handling and Storage

ESD (Electrostatic Discharge)

Electrostatic discharge occurs naturally in the environment. With the increase in voltage potential, the outlet of neutralization or discharge will be sought. If the acquired discharge route is through a semiconductor device, destructive damage will result.

ESD countermeasure methods should be developed and used to control potential ESD damage during handling in a factory environment at each manufacturing site.

MSL (Moisture Sensitivity Level)

Plastic encapsulated surface mount package is sensitive to damage induced by absorbed moisture and temperature.

Avago Technologies follows JEDEC Standard J-STD 020B. Each component and package type is classified for moisture sensitivity by soaking a known dry package at various temperatures and relative humidity, and times. After soak, the components are subjected to three consecutive simulated reflows.

The out of bag exposure time maximum limits are determined by the classification test describe below which corresponds to a MSL classification level 6 to 1 according to the JEDEC standard IPC/JEDEC J-STD-020B and J-STD-033.

ACPM-7381 is MSL3. Thus, according to the J-STD-033 p.11 the maximum Manufacturers Exposure Time (MET) for this part is 168 hours. After this time period, the part would need to be removed from the reel, de-taped and then re-baked. MSL classification reflow temperature for the ACPM-7381 is targeted at $260^{\circ} + 0/-5^{\circ}$ C. Figure 23 and Table 8 show typical SMT profile for maximum temperature of $260 + 0/-5^{\circ}$ C.

Table 6. ESD Classification

Pin #	Name	Description	HBM	CDM	Classification
1	Vcc1	Supply Voltage	$\pm 2000 V$	$\pm 200V$	Class 2
2	RF In	RF Input	$\pm 2000 V$	$\pm 200V$	Class 2
3	Vmode1	Control Voltage	$\pm 2000 V$	$\pm 200 V$	Class 2
4	Vmode0	Control Voltage	$\pm 2000 V$	$\pm 200V$	Class 2
5	Ven	Enable Voltage	$\pm 2000 V$	$\pm 200V$	Class 2
6	GND	Ground	$\pm 2000 V$	$\pm 200 V$	Class 2
7	GND	Ground	$\pm 2000 V$	$\pm 200 V$	Class 2
8	RF Out	RF Output	$\pm 2000 V$	$\pm 200V$	Class 2
9	GND	Ground	$\pm 2000 V$	$\pm 200V$	Class 2
10	Vcc2	Supply Voltage	$\pm 2000 V$	$\pm 200V$	Class 2

Note :

1. Module products should be considered extremely ESD sensitive

Table 7. Moisture Classification Level and Floor Life

1 Unlimited at =< 30°C/85% RH 2 1 year 2a 4 weeks 3 168 hours 4 72 hours 5 48 hours 5a 24 hours	MSL Level	Floor Life (out of bag) at factory ambient =< 30° C/60% RH or as stated
2a 4 weeks 3 168 hours 4 72 hours 5 48 hours 5a 24 hours	1	Unlimited at =< 30°C/85% RH
3 168 hours 4 72 hours 5 48 hours 5a 24 hours	2	1 year
4 72 hours 5 48 hours 5a 24 hours	2a	4 weeks
5 48 hours 5a 24 hours	3	168 hours
5a 24 hours	4	72 hours
	5	48 hours
	5a	24 hours
6 Mandatory bake before use. After bake, must be reflowed within the time limit specified on the label	6	Mandatory bake before use. After bake, must be reflowed within the time limit specified on the label

Note :

1. The MSL Level is marked on the MSL Label on each shipping bag.

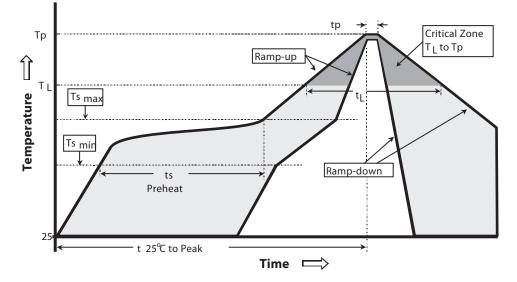


Figure 23. Typical SMT Reflow Profile for Maximum Temperature = $260 + 0/-5^{\circ}C$

Table 8. Typical SMT Reflow Profile for Maximum Temperature = $260+0/-5^{\circ}C$

,1	•						
Profile Feature	Sn-Pb Solder	Pb-Free Solder					
Average ramp-up rate (TL to TP)	3°C/sec max	3° C/sec max					
Preheat							
- Temperature Min (Tsmin)	100°C	150°C					
- Temperature Max (Tsmax)	150°C	200°C					
- Time (min to max) (ts)	60-120 sec	60-180 sec					
Tsmax to TL							
- Ramp-up Rate		3°C /sec max					
Time maintained above:							
- Temperature (TL)	183°C	217°C					
- Time (TL)	60-150 sec	60-150 sec					
Peak temperature (Tp)	240 +0/-5°C	260 +0/-5°C					
Time within 5°C of actual Peak Temperature (tp)	10-30 sec	20-40 sec					
Ramp-down Rate	6°C /sec max	6°C /sec max					
Time 25°C to Peak Temperature	6 min max.	8 min max.					

Storage Condition

Packages described in this document must be stored in sealed moisture barrier, antistatic bags. Shelf life in a sealed moisture barrier bag is 12 months at <40°C and 90% relative humidity (RH) J-STD-033 p.7.

Out-of-Bag Time Duration

After unpacking the device must be soldered to the PCB within 168 hours as listed in the J-STD-020B p.11 with factory conditions $<30^{\circ}$ C and 60% RH.

Baking

It is not necessary to re-bake the part if both conditions (storage conditions and out-of bag conditions) have been satisfied. Baking must be done if at least one of the conditions above have not been satisfied. The baking conditions are 125°C for 12 hours J-STD-033 p.8.

CAUTION

Tape and reel materials typically cannot be baked at the temperature described above. If out-of-bag exposure time is exceeded, parts must be baked for a longer time at low temperatures, or the parts must be de-reeled, detaped, re-baked and then put back on tape and reel. (See moisture sensitive warning label on each shipping bag for information of baking).

Board Rework

Component Removal, Rework and Remount

If a component is to be removed from the board, it is recommended that localized heating be used and the maximum body temperatures of any surface mount component on the board not exceed 200°C. This method will minimize moisture related component damage. If any component temperature exceeds 200°C, the board must be baked dry per 4-2 prior to rework and/or component removal. Component temperatures shall be measured at the top center of the package body. Any SMD packages that have not exceeded their floor life can be exposed to a maximum body temperature as high as their specified maximum reflow temperature.

Removal for Failure Analysis

Not following the above requirements may cause moisture/reflow damage that could hinder or completely prevent the determination of the original failure mechanism.

Baking of Populated Boards

Some SMD packages and board materials are not able to withstand long duration bakes at 125°C. Examples of this are some FR-4 materials, which cannot withstand a 24 hr bake at 125°C. Batteries and electrolytic capacitors are also temperature sensitive. With component and board temperature restrictions in mind, choose a bake temperature from Table 4-1 in J-STD 033; then determine the appropriate bake duration based on the component to be removed. For additional considerations see IPC-7711 andIPC-7721.

Derating due to Factory Environmental Conditions

Factory floor life exposures for SMD packages removed from the dry bags will be a function of the ambient environmental conditions. A safe, yet conservative, handling approach is to expose the SMD packages only up to the maximum time limits for each moisture sensitivity level as shown in Table 7. This approach, however, does not work if the factory humidity or temperature is greater than the testing conditions of 30°/60% RH. A solution for addressing this problem is to derate the exposure times based on the knowledge of moisture diffusion in the component package materials ref. JESD22-A120). Recommended equivalent total floor life exposures can be estimated for a range of humidities and temperatures based on the nominal plastic thickness for each device.

Table 9 lists equivalent derated floor lives for humidities ranging from 20-90% RH for three temperature, 20° , 25° , and 30° C.

This table is applicable to SMDs molded with novolac, biphenyl or multifunctional epoxy mold compounds. The following assumptions were used in calculating Table 9:

- 1. Activation Energy for diffusion = 0.35eV (smallest known value).
- 2. For $\leq 60\%$ RH, use Diffusivity = 0.121exp (-0.35eV/kT) mm2/s (this used smallest known Diffusivity @ 30°C).
- 3. For >60% RH, use Diffusivity = 1.320exp (-0.35eV/kT) mm2/s (this used largest known Diffusivity @ 30°C).

 Table 9. Recommended Equivalent Total Floor Life (days) @ 20°C, 25 °C & 30 °C For ICs with Novolac, Biphenyl and Multifunctional Epoxies (Reflow at same temperature at which the component was classified)

Maximum Percent Relative Humidity

Package Type and Body Thickness	Moisture Sensitivity Level	5%	10%	20 %	30%	40 %	50 %	60 %	70 %	80%	90 %	
Body Thickness ≥3.1 mm	Level 2a	∞	∞	∞	60	41	33	28	10	7	6	30°
Including		∞	∞	∞	78	53	42	36	14	10	8	25°
PQFPs >84 pin,		~~~~	~	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	103	69	57	47	19	13	10	20
PLCCs (square) All MQFPs	Level 3	∞	∞	10	9	8	7	7	5	4	4	30
or		00	~	13	11	10	9	9	7	6	5	25
All BGAs ≥1 mm		~~~	~	17	14	13	12	12	10	8	7	20
	Level 4	∞	5	4	4	4	3	3	3	2	2	30
		∞	6 8	5 7	5 7	5 7	5 7	4 6	3 5	3 4	3 4	25 20
		~~~~			-							
	Level 5	00	4	3	3	2	2	2	2	1	1	30
		∞	5 7	5 7	4 6	4 5	3 5	3 4	2 3	2 2	2 3	25 20
	Level 5a	~	2 3	1 2	1 2	1 2	1	1 2	1 1	1 1	1 1	30 25
		∞	5 5	2 4	2	2	2 3	2	2	2	2	20
D. J. 0.1	1											
Body 2.1 mm ≤ Thickness	Level 2a	∞	∞	∞	∞	86 148	39 51	28 37	4 6	3 4	2 3	30 25
$\leq$ 111cm ess $<3.1 \text{ mm}$ including		∞	∞	~	~	1 <del>4</del> 0 ∞	69	49	8	5	4	20
PLCCs (rectangular)	Level 3			19		9						30
18-32 pin	Level 3	∞	∞	19 25	12 15	9 12	8 10	7 9	3 5	2 3	2 3	30 25
SOICs (wide body)		~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	32	19	15	13	12	7	5	4	20
SOICs $\geq$ 20 pins,	Level 4		7	5	4	4	3	3	2	2	1	30
PQFPs ≤80 pins	Level 4	∞	9	7	4 5	5	3 4	4	2	2	2	25
		~	11	9	7	6	6	5	4	3	3	20
	Level 5	~~~~	4	3	3	2	2	2	1	1	1	30
		~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	5	4	3	3	3	3	2	1	1	25
		∞	6	5	5	4	4	4	3	3	2	20
	Level 5a	~	2	1	1	1	1	1	1	0.5	0.5	30
		~	2	2	2	2	2	2	1	1	1	25
		∞	3	2	2	2	2	2	2	2	1	20
Body Thickness <2.1 mm	Level 2a	∞	~	~	~	~	~~~~	28	1	1	1	30
including	2010.20	~	∞	∞	∞	∞	~	~	2	1	1	25
SOICs <18 pin		∞	∞	∞	∞	∞	∞	∞	2	2	1	20
All TQFPs, TSOPs	Level 3	∞	∞	~	∞	∞	11	7	1	1	1	30
Oľ All DC As, <1 mm hadu		∞	∞	∞	∞	∞	14	10	2	1	1	25
All BGAs <1 mm body thickness		∞	∞	∞	∞	∞	20	13	2	2	1	20
נוונתודסס	Level 4	~	~	~	9	5	4	3	1	1	1	30
		∞	∞	∞	12	7	5	4	2	1	1	25
		~	∞	~	17	9	7	6	2	2	1	20
	Level 5	∞	∞	13	5	3	2	2	1	1	1	30
		∞	∞	18	6	4	3	3	2	1	1	25
		~	∞	26	8	6	5	4	2	2	1	20
	Level 5a	∞	10	3	2	1	1	1	1	1	0.5	30
		∞	13	5	3	2	2	2	1	1	1	25
		∞	18	6	4	3	2	2	2	2	1	20

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